## 捷多邦,专业PCB打样工**54AQ不16825**共**2**4ACT16825 18-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCAS155B - JANUARY 1991 - REVISED APRIL 1996

- Members of the Texas Instruments
  Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- Provide Extra Data Width Necessary for Wider Address/Data Paths or Buses With Parity
- Flow-Through Architecture Optimizes
  PCB Layout
- Distributed V<sub>CC</sub> and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Spacings

#### description

The 'ACT16825 18-bit buffers/drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 'ACT16825 can be used as two 9-bit buffers or one 18-bit buffer. They provide true data from A to Y.

The 3-state control gate is a 2-input NOR gate; therefore, if either output-enable (OE1 or OE2) input is high, all nine affected outputs are in the high-impedance state.

54ACT16825 . . . DW PACKAGE 74ACT16825 . . . DL PACKAGE (TOP VIEW)

10E1	1	56	10E2
1Y1	2	55	1A1
1Y2 [	3	54	1A2
GND [	4	53	GND
1Y3 [	5	52	] 1A3
1Y4 [	6	51	] 1A4
V <sub>CC</sub> [	7	50	] v <sub>cc</sub>
1Y5 [	8	49	] 1A5
1Y6 [	9	48	1A6
1Y7 [	10	47	] 1A7
GND [	11	46	GND
1Y8 [	12	45	] 1A8
1Y9 [	13	44	] 1A9
GND [	14	43	GND
GND [	15	42	GND
2Y1 [	16	41	2A1
2Y2 [	17	40	2A2
GND [	18	39	GND
2Y3 [	19	38	] 2A3
2Y4 [	20	37	2A4
2Y5 [	21	36	2A5
V <sub>CC</sub> [	22	35	Vcc
2Y6	23	34	2A6
2Y7 [	24	33	2A7
GND [	25	32	GND
2Y8 [	26	31	2A8
2Y9 [	27	30	2A9
20E1	28	29	20E2
			I

The 74ACT16825 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16825 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74ACT16825 is characterized for operation from –40°C to 85°C.

# FUNCTION TABLE (each 9-bit section)

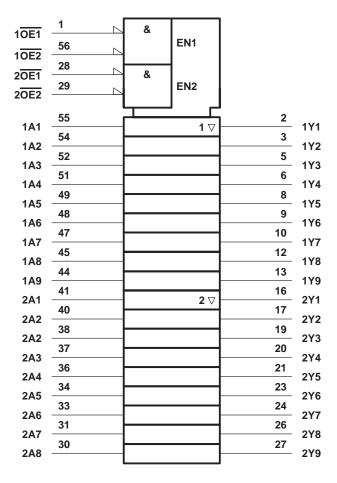
734	INPUTS	OUTPUT	
OE1	OE2	Α	Y
L	L	L	L
L	L	Н	Н
Н	X	Χ	Z
Х	Н	Χ	Z

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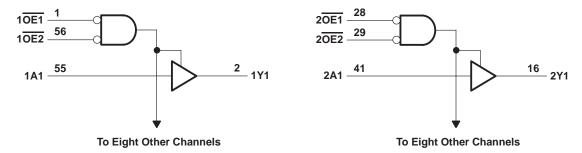


#### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)





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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)–C	$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V <sub>O</sub> (see Note 1)C	$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through V <sub>CC</sub> or GND	±450 mA
Maximum package power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2): DL package	1.4 W
Storage temperature range, T <sub>Stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions (see Note 3)

		54ACT16825		74ACT16825			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
VIL	Low-level input voltage		Š	0.8			0.8	V
VI	Input voltage	0	200	VCC	0		VCC	V
Vo	Output voltage	0	7,	Vcc	0		Vcc	V
IOH	High-level output current		3	-24			-24	mA
lOL	Low-level output current	20	7	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>2.</sup> The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS	Vaa	T,	<sub>Δ</sub> = 25°C		54ACT	16825	74ACT16825		UNIT		
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
	I <sub>OH</sub> = -50 μA	4.5 V	4.4			4.4		4.4				
	ΙΟΗ = -30 μΑ	5.5 V	5.4			5.4		5.4				
Voн	I <sub>OH</sub> = -24 mA	4.5 V	3.94			3.8		3.8		V		
	IOH = -24 IIIA	5.5 V	4.94			4.8		4.8				
	I <sub>OH</sub> = -75 mA <sup>†</sup>	5.5 V				3.85	N	3.85		7		
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1			
	ΙΟΣ = 30 μΑ	5.5 V			0.1	4	0.1		0.1			
VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36	40	0.44		0.44	0.44 V 0.44		
	10L = 24 111A	5.5 V			0.36	20	0.44		0.44			
	I <sub>OL</sub> = 75 mA <sup>†</sup>					Oy	1.65		1.65			
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1	y	±1		±1	μΑ		
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5		±5	μΑ		
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ		
ΔI <sub>CC</sub> ‡	One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	5.5 V			0.9		1		1	mA		
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4						pF		
Co	$V_O = V_{CC}$ or GND	5 V		16						pF		

<sup>†</sup>Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	չ = 25°C	;	54ACT	16825	74ACT	16825	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
<sup>t</sup> PLH	А		4.1	7.5	9.3	4.1	10.5	4.1	10.5	ns
<sup>t</sup> PHL	A	' [	3.1	7.5	9.6	3.1	10.3	3.1	10.3	119
<sup>t</sup> PZH	<del></del>	V	3.3	7.9	9.9	3.3	11	3.3	11	no
<sup>t</sup> PZL	ŌĒ	, , ,	4.1	9.5	12.1	4.1	13.2	4.1	13.2	ns
<sup>t</sup> PHZ	<del></del>	V	5.7	9	10.8	5.7	11.5	5.7	11.5	no
tPLZ	OE	ī	5.5	8.5	10	5.5	10.6	5.5	10.6	ns

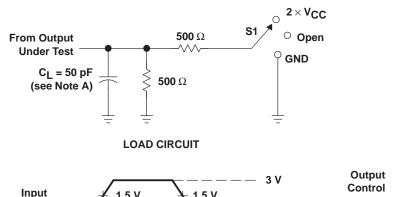
## operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

	PARAMETER			TEST CONDITIONS		
C . Power dissination capacitance		Outputs enabled	C. 50 pF		42	nE.
Ср	d Power dissipation capacitance	Outputs disabled	$C_L = 50 \text{ pF},$	f = 1 MHz	12	pF

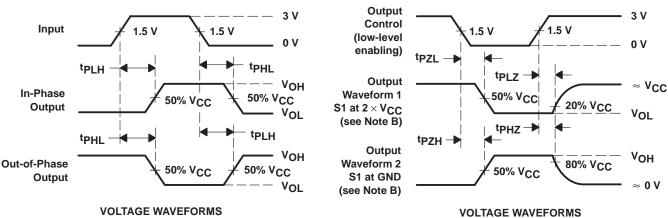


<sup>‡</sup>This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
tPLH/tPHL	Open
tPLZ/tPZL	2 × V <sub>CC</sub>
tPHZ/tPZH	GND



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 3 \ ns$ ,  $t_f = 3 \ ns$ .
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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